SKM 800 GA 126 D

SEMITRANS 4

Trench IGBT Modules

SKM 800 GA 126 D

Preliminary Data

Features

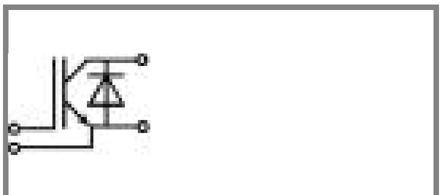
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability, self limiting to 6 x I_C

Typical Applications

- AC inverter drives
- UPS
- Electronic welders

Remarks

- $I_{DC} \leq$ 500A limited by terminals



GA

Absolute Maximum Ratings	T_{case} = 25°C, unless otherwise specified		
Symbol	**Conditions**	**Values**	**Units**
IGBT			
V_{CES}		1200	V
I_C	T_{case} = 25 (80) °C	960 (620)	A
I_{CRM}	T_{case} = 25 (80) °C, t_p = 1 ms	1920 (1240)	A
V_{GES}		±20	V
T_{vj}, (T_{stg})	$T_{OPERATION} \leq T_{stg}$	-40 ... +150 (125)	°C
V_{isol}	AC, 1 min.	2500	V
Inverse diode			
I_F = - I_C	T_{case} = 25 (125) °C	680 (470)	A
I_{FRM}	T_{case} = 25 (80) °C, t_p < 1 ms	1920 (1240)	A
I_{FSM}	t_p = 10 ms; sin.; T_j = 150 °C	3600	A
Freewheeling diode			
I_F = - I_C	T_{case} = °C		A
I_{FRM}	T_{case} = () °C, t_p < ms		A
I_{FSM}	t_p = ms; ; T_j = °C		A

Characteristics	T_{case} = 25°C, unless otherwise specified				
Symbol	**Conditions**	**min.**	**typ.**	**max.**	**Units**
IGBT					
$V_{GE(th)}$	V_{GE} = V_{CE}, I_C = 16 mA	5	5,8	6,5	V
I_{CES}	V_{GE} = 0, V_{CE} = V_{CES}, T_j = 25 (125) °C			1	mA
$V_{CE(TO)}$	T_j = 25 (125) °C		1 (0,9)	1,15	V
r_{CE}	V_{GE} = 15 V, T_j = 25 (125) °C		1,2 (1,8)	1,7	mΩ
$V_{CE(sat)}$	I_C = 600 A, V_{GE} = 15 V, chip level		1,7 (2)	2,15	V
C_{ies}			42		nF
C_{oes}	V_{GE} = 0, V_{CE} = 25 V, f = 1 MHz		3,3		nF
C_{res}			3,1		nF
L_{CE}				20	nH
$R_{CC'+EE'}$	resistance, terminal-chip °C		0,18 (0,22)		mΩ
$t_{d(on)}$	V_{CC} = 600 V, I_C = 600 A		220		ns
t_r	R_{Gon} = R_{Goff} = 3 Ω, T_j = 125 °C		100		ns
$t_{d(off)}$	V_{GE} ± 15 V		860		ns
t_f			135		ns
E_{on} (E_{off})			65 (95)		mJ
Inverse diode					
V_F = V_{EC}	I_F = 600 A; V_{GE} = 0 V; T_j = 25 (125) °C		1,7 (1,8)	1,9 (1,9)	V
$V_{T(TO)}$	T_j = 25 (125) °C		1 (0,8)	1,1 (0,9)	V
r_T	T_j = 25 (125) °C		1,2 (1,6)	1,2 (1,7)	mΩ
I_{RRM}	I_F = 600 A; T_j = 125 ( ) °C		540		A
Q_{rr}	di/dt = 6000 A/µs		125		µC
E_{rr}	V_{GE} = 0 V		59		mJ
FWD					
V_F = V_{EC}	I_F = A; V_{GE} = V, T_j = () °C				V
V_{TO}	T_j = () °C				V
r_T	T_j = () °C				mΩ
I_{RRM}	I_F = A; T_j = ( ) °C				A
Q_{rr}	V_{GE} = V				µC
E_{rr}					mJ
Thermal characteristics					
$R_{th(j-c)}$	per IGBT			0,042	K/W
$R_{th(j-c)D}$	per Inverse Diode			0,09	K/W
$R_{th(j-c)FD}$	per FWD				K/W
$R_{th(c-s)}$	per module			0,038	K/W
Mechanical data					
M_s	to heatsink (M6)	3		5	Nm
M_t	for terminals (M5)	2,5		5	Nm
w				330	g

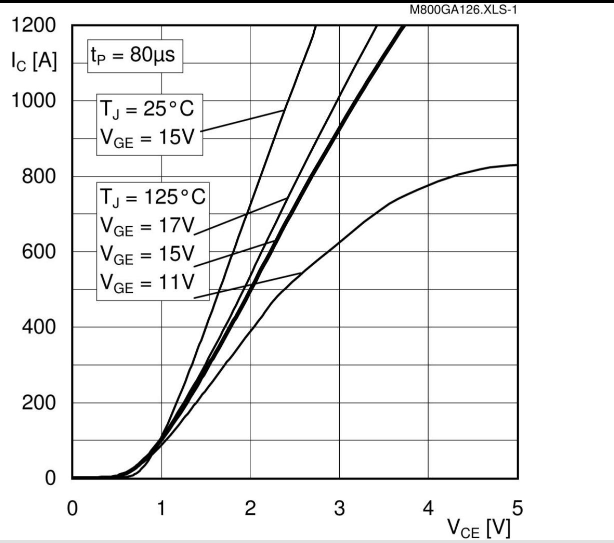


Fig. 1 Typ. output characteristic, inclusive $R_{CC'+EE'}$

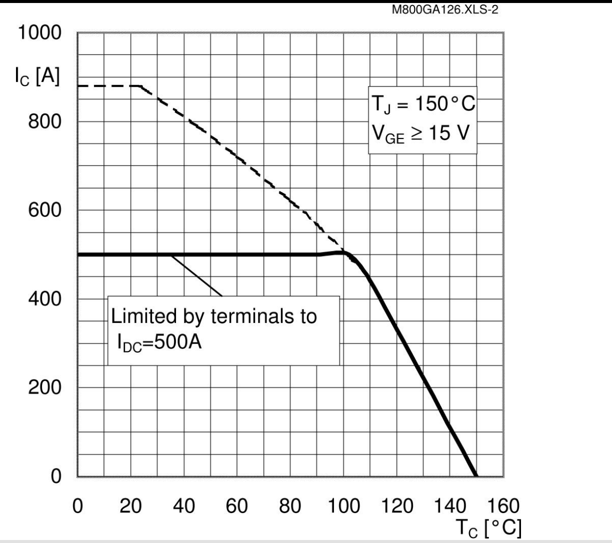


Fig. 2 Rated current vs. temperature $I_C = f(T_C)$

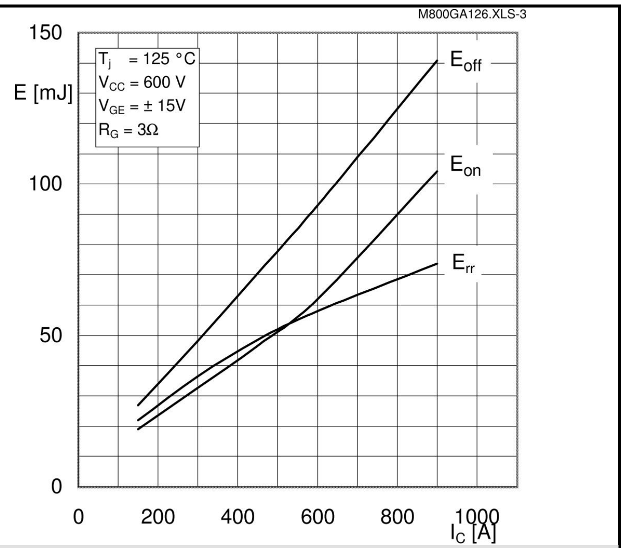


Fig. 3 Typ. turn-on /-off energy = f (I_C)

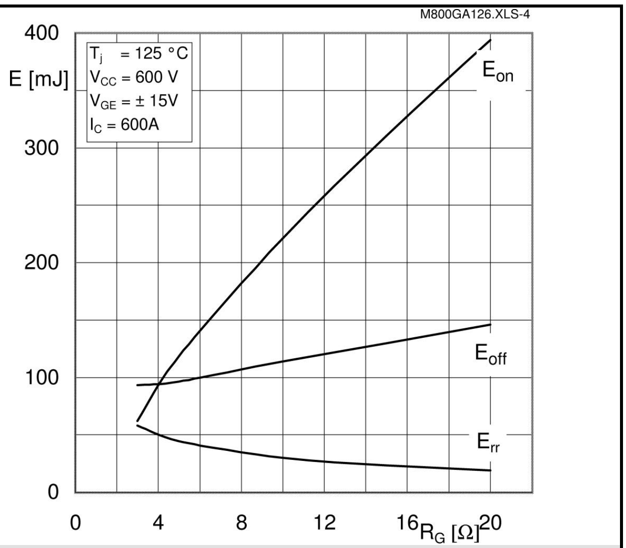


Fig. 4 Typ. turn-on /-off energy = f (R_G)

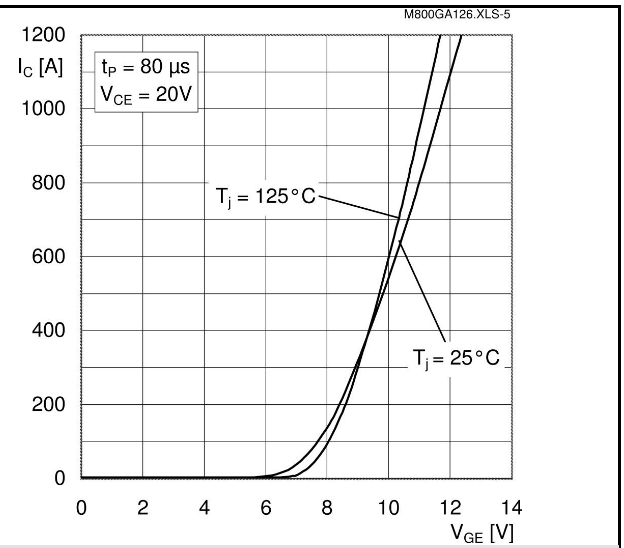


Fig. 5 Typ. transfer characteristic

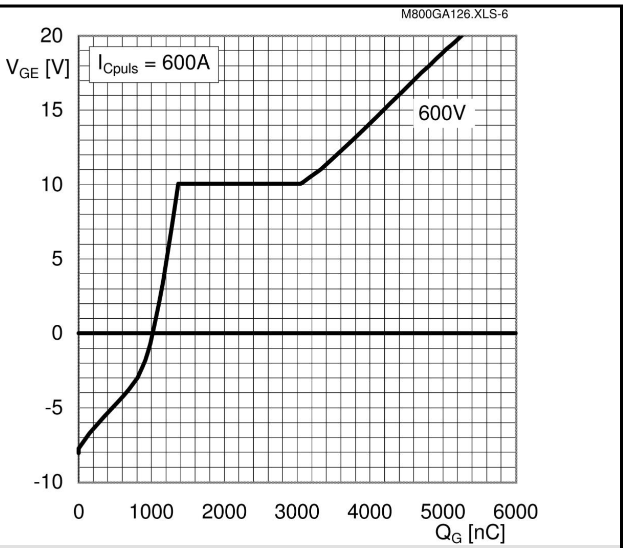


Fig. 6 Typ. gate charge characteristic

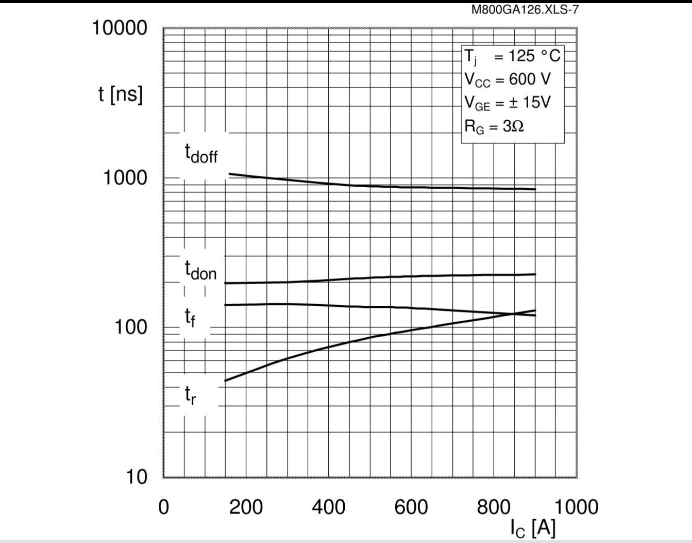


Fig. 7 Typ. switching times vs. I_C

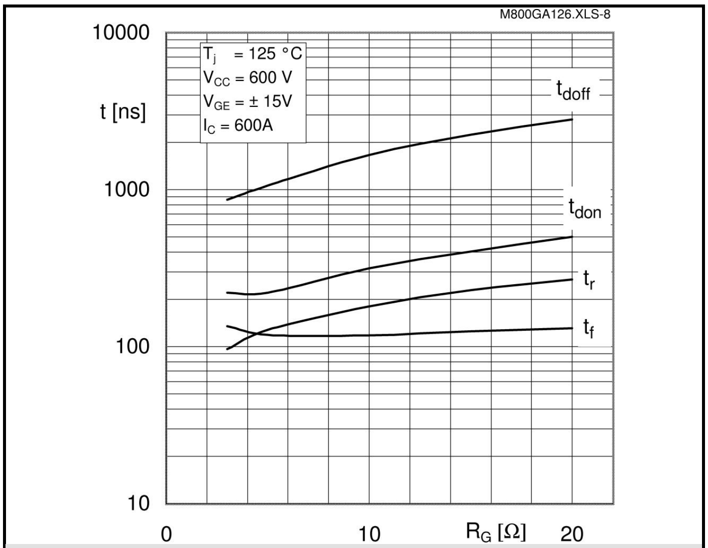


Fig. 8 Typ. switching times vs. gate resistor R_G

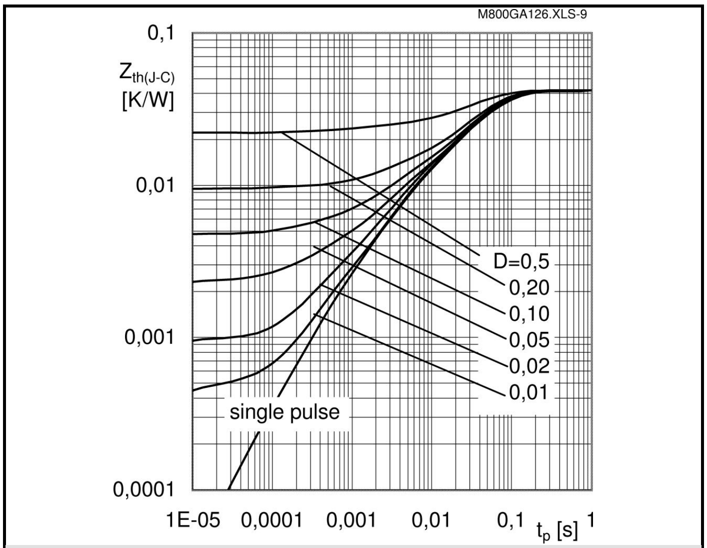


Fig. 9 Transient thermal impedance of IGBT

$Z_{thp(j-c)} = f(t_p)$; $D = t_p/t_c = t_p*f$

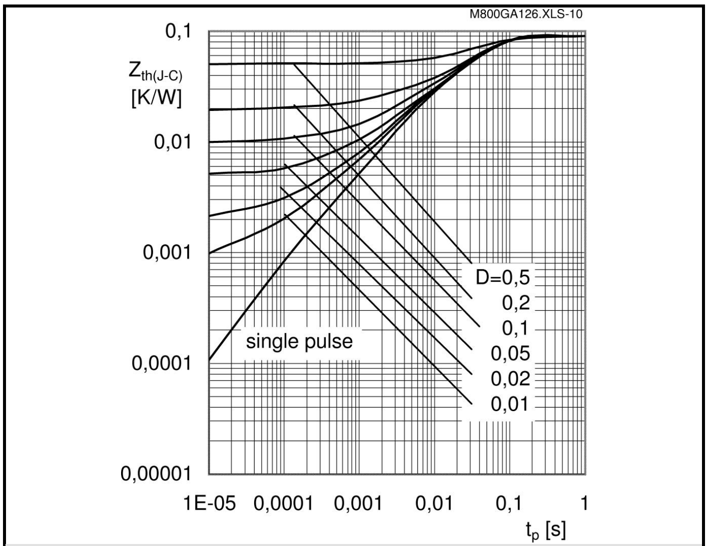


Fig. 10 Transient thermal impedance of Inverse CAL Diode

$Z_{thp(j-c)} = f(t_p)$; $D = t_p/t_c = t_p*f$

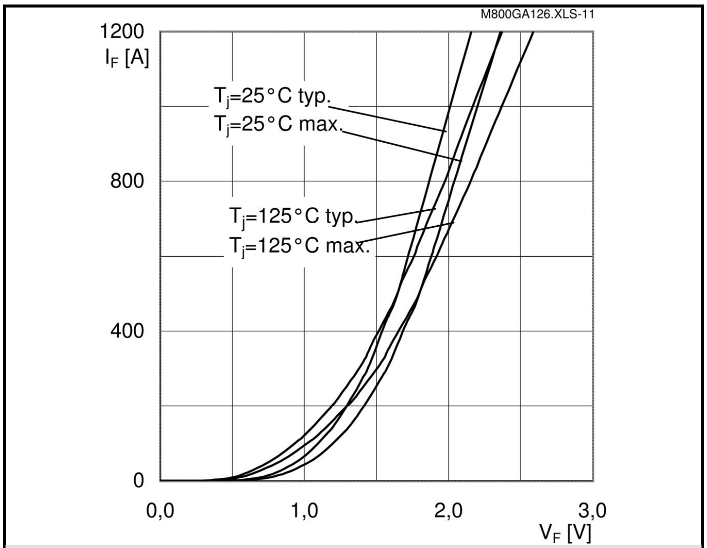


Fig. 11 CAL diode forward characteristic

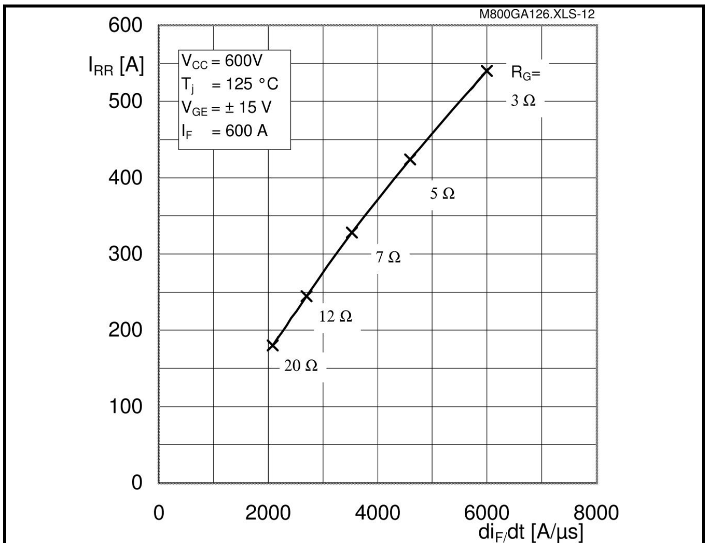


Fig. 12 Typ. CAL diode peak reverse recovery current

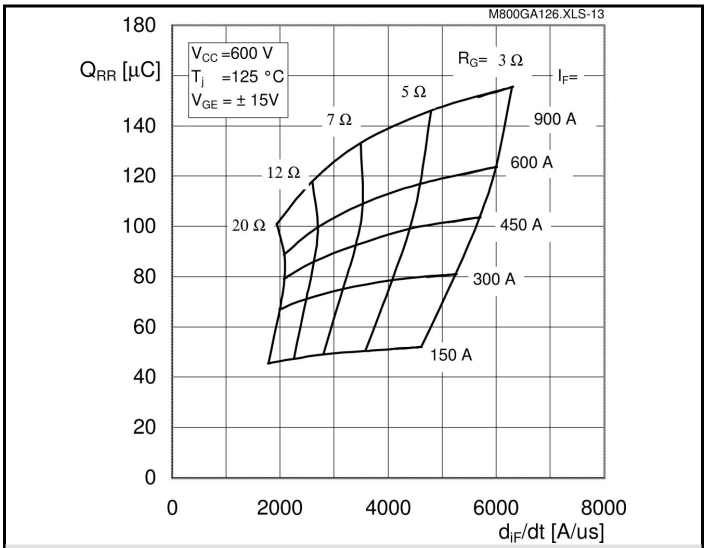
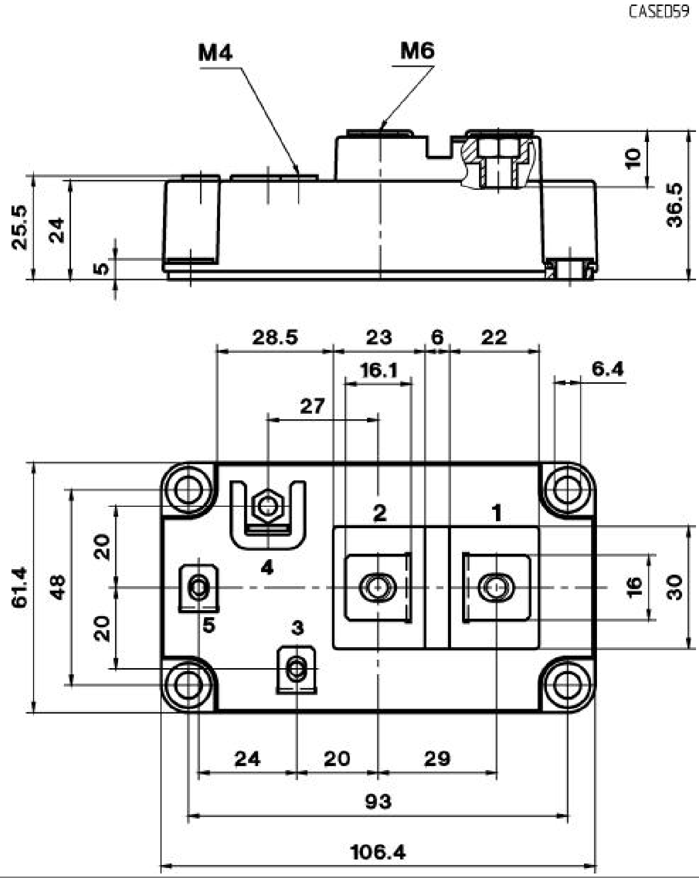


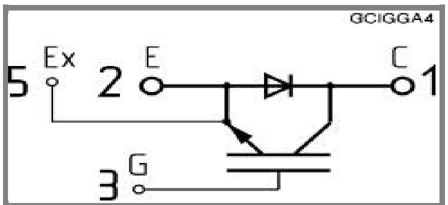
Fig. 13 Typ. CAL diode recovered charge

UL Recognized
File no. E 63 532

Dimensions in mm



Case D 59



Case D59 GA

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

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